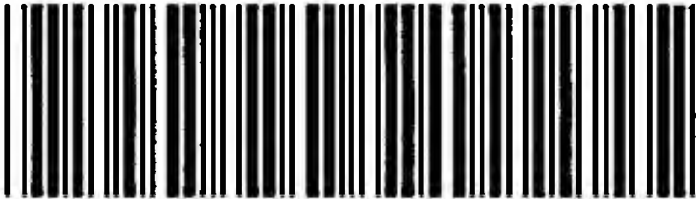


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/707,681	TU, CHIN-FA	
	Examiner	Art Unit	
	Matthew G. Kayrish	2627	

SEARCHED			
Class	Subclass	Date	Examiner
720	610	7/31/2006	MK
720	639	7/31/2006	MK
720	637	7/31/2006	MK
720	636	7/31/2006	MK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (USPG-PUB, USPAT, USOCR, EPO, JPO, IBM_TDB, DERWENT) (See Attached Search History)	7/31/2006	MK